

ABSTRACT

The present disclosure provides a method and a system for inspecting goods. The method comprises steps of: obtaining a transmission image of inspected goods; processing the transmission image to obtain a suspicious region; extracting local texture features of the suspicious region and classifying the local texture features of the suspicious region based on a pre-created model to obtain a classification result; extracting a contour line shape feature of the suspicious region and comparing the contour line shape feature with a pre-created standard template to obtain a comparison result; and determining that the suspicious region contains a high atomic number matter based on the classification result and the comparison result.

Fig. 2